

<b>Notice of References Cited</b>	Application/Control No. 10/578,994		Applicant(s)/Patent Under Reexamination GRONAU ET AL.	
	Examiner Hau V. Phan		Art Unit 3618	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,695,020	12-1997	Nishimura, Eiji	180/169
*	B	US-5,393,277	02-1995	White et al.	477/108
*	C	US-5,983,161	11-1999	Lemelson et al.	701/301
*	D	US-2005/0004753	01-2005	Weiland et al.	701/208
*	E	US-5,303,952	04-1994	Shermetaro et al.	280/731
*	F	US-6,275,733	08-2001	Park et al.	607/18
*	G	US-6,498,967	12-2002	Hopkins et al.	701/1
*	H	US-6,892,126	05-2005	Tashiro et al.	701/54
*	I	US-6,470,252	10-2002	Tashiro et al.	701/51
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.